

MAY 16 2003

FORM PTO-1449 (Modified)

US DEPARTMENT OF COMMERCE

Docket No.

Application No.

Approved for use through 10/31/2002

US Patent and Trademark Office

50623.168

09/872,135

INFORMATION DISCLOSURE CITATION **in an Application**

Applicant

Brandon J. Yoe et al.

(Use several sheets if necessary)

Filing Date

May 31, 2001

Group Art Unit

3749

U.S. PATENT DOCUMENTS

Examiner Initial	Ref. No.	Document Number	Date of Patent	Name	Class	Subclass	Filing Date if Appropriate
CTN	A1	4,733,665	3/29/88	Palmaz	128	343	
	A2	4,800,882	1/31/89	Gianturco	128	343	
	A3	4,886,062	12/12/89	Wiktor	128	343	
	A4	4,931,287	6/5/90	Bae et al.	424	484	
	A5	4,994,560	2/19/91	Kruper, Jr. et al.	534	10	
	A6	5,040,548	8/20/91	Yock	128	898	
	A7	5,064,435	11/12/91	Porter	623	12	
	A8	5,100,429	3/31/92	Sinofsky et al.	606	195	
	A9	5,213,561	5/25/93	Weinstein et al.	600	7	
	A10	5,229,172	7/20/93	Cahalan et al.	427	536	
	A11	5,258,419	11/2/93	Rolando et al.	522	109	
	A12	5,278,200	1/11/94	Coury et al.	523	112	
	A13	5,308,641	5/3/94	Cahalan et al.	427	2	
	A14	5,336,518	8/9/94	Narayanan et al.	623	1	
	A15	5,342,283	8/30/94	Good	600	8	
	A16	5,342,621	8/30/94	Eury	424	423	
	A17	5,344,455	9/6/94	Keogh et al.	623	11	
	A18	5,350,800	9/27/94	Verhoeven et al.	525	54.2	
	A19	5,366,504	11/22/94	Andersen et al.	623	11	
	A20	5,411,466	5/2/95	Hess	600	3	
	A21	5,415,938	5/16/95	Cahalan et al.	428	409	

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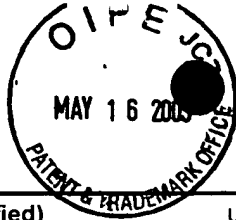


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CTN	A22	5,429,618	7/4/95	Keogh	604	266	
	A23	5,443,496	8/22/95	Schwartz et al.	623	1	
	A24	5,464,450	11/7/95	Buscemi et al.	623	6	
	A25	5,476,509	12/19/95	Keogh et al.	623	1	
	A26	5,500,013	3/19/96	Buscemi et al.	623	1	
	A27	5,551,954	9/3/96	Buscemi et al.	623	1	
	A28	5,554,182	9/10/96	Dinh et al.	623	1	
	A29	5,571,166	11/5/96	Dinh et al.	623	1	
	A30	5,591,224	1/7/97	Schwartz et al.	623	1	
	A31	5,591,227	1/7/97	Dinh et al.	623	1	
	A32	5,599,352	2/4/97	Dinh et al.	623	1	
	A33	5,624,411	4/29/97	Tuch	604	265	
	A34	5,628,785	5/13/97	Schwartz et al.	623	1	
	A35	5,637,113	6/10/97	Tartaglia et al.	623	1	
	A36	5,649,977	7/22/97	Campbell	623	1	
	A37	5,674,242	10/7/97	Phan et al.	606	198	
	A38	5,693,085	12/2/97	Buirge et al.	623	1	
	A39	5,693,376	12/2/97	Fetherston et al.	427	523	
	A40	5,697,967	12/16/97	Dinh et al.	623	1	
	A41	5,702,818	12/30/97	Cahalan et al.	428	409	
	A42	5,707,385	1/13/98	Williams	606	192	
✓	A43	5,711,812	1/27/98	Chapek et al.	118	723 E	
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Examiner Initial	Ref. No.	Document Number	Date of Patent	Name	Class	Subclass	Filing Date if Appropriate
CTN	A44	5,713,949	2/3/98	Jayaraman	623	1	
	A45	5,722,984	3/3/98	Fischell et al.	606	198	
	A46	5,766,710	6/16/98	Turnlund et al.	428	36.1	
	A47	5,769,883	6/23/98	Buscemi et al.	623	1	
	A48	5,769,884	6/23/98	Solovay	623	1	
	A49	5,811,151	9/22/98	Hendriks et al.	427	2.24	
	A50	5,824,048	10/20/98	Tuch	623	1	
	A51	5,826,586	10/27/98	Mishra et al.	128	898	
	A52	5,843,172	12/1/98	Yan	623	1	
	A53	5,858,556	1/12/99	Eckhart et al.	428	586	
	A54	5,858,990	1/12/99	Walsh	514	44	
	A55	5,857,998	1/12/99	Barry	604	96	
	A56	5,866,113	2/2/99	Hendriks et al.	424	78.17	
	A57	5,893,840	4/13/99	Hull et al.	604	96	
	A58	5,897,911	4/27/99	Loeffler	427	2.25	
	A59	5,902,631	5/11/99	Wang et al.	427	2.1	
	A60	5,916,234	6/29/99	Lam	606	198	
▼	A61	5,925,552	7/20/99	Keogh et al.	435	174	
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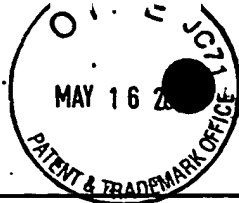


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Examiner Initial	Ref. No.	Document Number	Date of Patent	Name	Class	Subclass	Filing Date if Appropriate
CTN	A62	5,928,916	7/27/99	Keogh	435	174	
	A63	5,968,091	10/19/99	Pinchuk et al.	623	1	
	A64	5,968,092	10/19/99	Buscemi et al.	623	1	
	A65	5,972,027	10/26/99	Johnson	623	1	
	A66	5,972,029	10/26/99	Fuisz	623	1	
	A67	5,980,564	11/9/00	Stinson	623	1	
	A68	5,997,517	12/7/99	Whitbourne	604	265	
	A69	6,013,099	1/11/00	Dinh et al.	623	1	
	A70	6,019,789	2/1/00	Dinh et al.	623	1	
	A71	6,024,918	2/15/00	Hendriks et al.	422	44	
	A72	6,033,719	3/7/00	Keogh	427	2.12	
	A73	6,042,606	3/28/00	Frantzen	623	1	
	A74	6,042,875	3/28/00	Ding et al.	427	2.24	
	A75	6,071,305	6/6/00	Brown et al.	623	1	11/24/97
	A76	6,080,190	6/27/00	Schwartz	623	1	4/29/98
	A77	6,093,199	6/25/00	Brown et al.	606	200	8/5/98
	A78	6,099,559	8/8/00	Nolting	623	1.16	5/28/98
	A79	6,099,561	8/8/00	Alt	623	1.44	10/20/98
	A80	6,106,454	8/22/00	Berg et al.	600	3	6/17/97
	A81	6,110,483	8/29/00	Whitbourne et al.	424	423	6/23/97
	A82	6,140,127	10/31/00	Sprague	435	395	2/18/98
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CTN	A83	6,140,431	10/31/00	Kinker et al.	526	79	2/12/98
	A84	6,168,619	1/2/01	Dinh et al.	623	1.13	10/16/98
	A85	6,203,551	3/20/01	Wu	606	108	10/4/99
	A86	6,214,901	4/10/01	Chudzik et al.	523	113	4/15/99
	A87	6,224,894	5/1/01	Jamiolkowski et al.	424	426	8/11/00
	A88	6,231,590	5/15/01	Slaikeu et al.	606	200	7/12/99
	A89	6,242,041	6/5/01	Katoot et al.	427	2.24	11/10/98
	A90	6,253,443	7/3/01	Johnson	29	557	10/18/99
	A91	6,254,632	7/3/01	Wu et al.	623	1.15	9/28/00
	A92	6,258,121	7/10/01	Yang et al.	623	1.46	7/2/99
	A93	6,262,034	7/17/01	Mathiowitz et al.	514	44	11/25/97
	A94	6,273,913	8/14/01	Wright et al.	623	1.42	4/16/98
	A95	6,287,628	9/11/01	Hossainy et al.	427	2.3	9/3/99
	A96	6,319,520	11/20/01	Wuthrich et al.	424	482	6/27/00
	A97	6,344,035	2/5/02	Chudzik et al.	604	265	10/20/00
	A98	6,379,379	4/30/02	Wang	623	1.31	8/13/99
	A99	6,379,381	4/30/02	Hossainy et al.	623	1.42	9/3/99
	A100	6,413,272	7/2/02	Igaki	623	1.15	2/28/01
	A101	6,488,701	12/3/02	Nolting et al.	623	1.13	3/31/98
	A102	09/697,106		Hossainy et al.			10/26/00
	A103	09/834,012		Hossainy et al.			4/12/01

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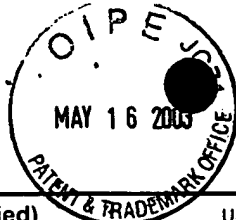
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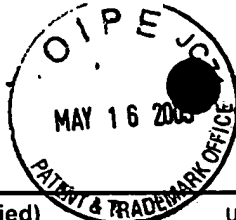
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Examiner Initial	Ref. No.	Document Number	Date of Publication	Country	Class	Subclass	Translation	
							Yes	No
CTN	B1	19916086	10/14/99	DE			X	
	B2	EP 0 627 226	12/7/94	European				
	B3	EP 0 701 803	3/20/96	European				
	B4	EP 0 850 604	7/1/98	European				
	B5	EP 0 972 498	1/19/00	European				
	B6	EP 0 850 651	6/28/00	European				
	B7	EP 1 103 234	5/30/01	European			X	
	B8	WO 90/01969	3/8/90	PCT				
	B9	WO 98/23228	6/4/98	PCT				
	B10	WO 01/91918	12/6/01	PCT				
	B11	WO 02/47731	6/20/02	PCT				
	B12							
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CTN	C1	Fischell et al., "Low-Dose, β -Particle Emission from 'Stent' Wire Results in Complete, Localized Inhibition of Smooth Muscle Cell Proliferation", Circulation, Vol. 90(6):2956-2963, December 1994.						
	C2	Hehrlein et al., "Low-Dose Radioactive Endovascular Stents Prevent Smooth Muscle Cell Proliferation and Neointimal Hyperplasia in Rabbits", Circulation, Vol. 92(6):1570-1575, September 15, 1995.						
	C3	Liermann et al., "Prophylactic Endovascular Radiotherapy to Prevent Intimal Hyperplasia after Stent Implantation in Femoropopliteal Arteries", CardioVascular and Interventional Radiology 17:12-16, 1994.						
	C4	Malik et al., Development of an Energetic Ion Assisted Mixing and Deposition Process for TiN_x and Diamondlike Carbon Films, Using a Co-axial Geometry in Plasma Source Ion Implantation, J. Vac. Sci. Technol. A 15(6):2875-2879 (Nov./Dec. 1997).						
	C5	Malik et al., Overview of Plasma Source Ion Implantation Research at University of Wisconsin-Madison, J. Vac. Sci. Technol. B 12(2):843-849 (Mar./Apr. 1994).						
	C6	Malik et al., Sheath Dynamics and Dose Analysis for Planar Targets in Plasma Source Ion Implantation, Plasma Sources Sci. Technol. 2:81-85 (1993).						
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LTN	C7	Scheuer et al., <i>Model of Plasma Source Ion Implantation in Planar, Cylindrical, and Spherical Geometries</i> , J. Appl. Phys. 67(3):1241-1245 (Feb. 1990).
	C8	Serruys et al., <i>I Like the Candy, I Hate the Wrapper; the ³²P Radioactive Stent</i> , Circulation 101:3-7 (Jan. 2000).
	C9	Shamim et al., <i>Measurement of Electron Emission Due to Energetic Ion Bombardment in Plasma Source Ion Implantation</i> , J. Appl. Phys. 70(9):4756-4759 (Nov. 1991).
	C10	Shamim et al., <i>Measurements of Spatial and Temporal Sheath Evolution for Spherical and Cylindrical Geometries in Plasma Source Ion Implantation</i> , J. Appl. Phys. 69(5):2904-2908 (March 1991).
	C11	Wiesendanger et al., <i>Contributions Of Scanning Probe Microscopy And Spectroscopy To The Investigation And Fabrication Of Nanometer-Scale Structures</i> , J. Vac. Sci. Technol. B, 12(2):515-529 (Mar./Apr. 1994).
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